

L Number	Hits	Search Text	DB	Time stamp
1	0	circuit adj simulation same token	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:24
2	83	circuit adj simulation and token	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:24
3	0	circuit adj simulation and token same (report design adj information)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:26
4	46	circuit adj simulation and token same information	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:31
5	11	circuit adj design same (test evaluat\$4) same token	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:32
6	30	circuit adj design same (test evaluat\$4) and token same information	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:45
7	31	circuit adj design same (test evaluat\$4) same design adj information	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/26 14:46